

### **AUTOMOTIVE GRADE**

Logic Level

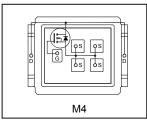
Advanced Process Technology

- Optimized for Automotive Motor Drive, DC-DC and other Heavy Load Applications
- Exceptionally Small Footprint and Low Profile
- High Power Density
- Low Parasitic Parameters
- Dual Sided Cooling
- 175°C Operating Temperature
- Repetitive Avalanche Capability for Robustness and Reliability
- Lead free, RoHS and Halogen free
- Automotive Qualified \*

 $V_{(BR)DSS}$  40V  $R_{DS(on)}$  typ. 2.2mΩ

Automotive DirectFET® Power MOSFET ②

max.3.0mΩ $I_{D (Silicon Limited)}$ 112A $Q_{g (typical)}$ 52nC





Applicable DirectFET® Outline and Substrate Outline ①

SB SC M2	M4	L4	L6 L8	
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## **Description**

The AUIRL7736M2 combines the latest Automotive HEXFET® Power MOSFET Silicon technology with the advanced DirectFET® packaging technology to achieve exceptional performance in a package that has the footprint of an SO-8 or 5X6mm PQFN and only 0.7mm profile. The DirectFET® package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET® package allows dual sided cooling to maximize thermal transfer in automotive power systems.

his HEXFET® Power MOSFET is designed for applications where efficiency and power density are of value. The advanced DirectFET® packaging platform coupled with the latest silicon technology allows the AUIRL7736M2 to offer substantial system level savings and performance improvement specifically in high frequency DC-DC, motor drive and other heavy load applications on ICE, HEV and EV platforms. The AUIRL7736M2 can be utilized together with the AUIRL7732S2 as a sync/control MOSFET pair in a buck converter topology. This MOSFET utilizes the latest processing techniques to achieve low on-resistance and low Qg per silicon area. Additional features of this MOSFET are 175°C operating junction temperature and high repetitive peak current capability. These features combine to make this MOSFET a highly efficient, robust and reliable device for high current automotive applications.

Daga Dawi Numbar	Doolsono Turo	Standard	Pack	Ordereble Deut Neurober
Base Part Number Package Type		Form	Quantity	Orderable Part Number
AUIRL7736M2	DirectFET Medium Can	Tape and Reel	4800	AUIRL7736M2TR

### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
$V_{DS}$	Drain-to-Source Voltage	40	V
$V_{GS}$	Gate-to-Source Voltage	±16	V
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) 4	112	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) @	79	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	179	Α
I <sub>D</sub> @ T <sub>A</sub> = 25°C			]
I <sub>DM</sub>	Pulsed Drain Current ⑦	450	
P <sub>D</sub> @T <sub>C</sub> = 25°C Power Dissipation ④		63	10/
P <sub>D</sub> @T <sub>A</sub> = 25°C			W
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ®	68	I
E <sub>AS</sub> (Tested)	Single Pulse Avalanche Energy ®	119	mJ
I <sub>AR</sub>	Avalanche Current ©	Car Fig. 40, 47, 40a, 40b	Α
E <sub>AR</sub> Repetitive Avalanche Energy ©		See Fig. 16, 17, 18a, 18b	mJ
T <sub>P</sub>	Peak Soldering Temperature	260	
TJ	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		

HEXFET® is a registered trademark of Infineon.

2015-10-29

<sup>\*</sup>Qualification standards can be found at www.infineon.com



# **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JA}$	Junction-to-Ambient ③		60	
$R_{ heta JA}$	Junction-to-Ambient ® 12.5 —			
$R_{\theta JA}$	Junction-to-Ambient ®	20		°C/W
$R_{ heta J ext{-}Can}$	Junction-to-Can 4 ® — 2.4		2.4	
$R_{\theta J\text{-PCB}}$	Junction-to-PCB Mounted	1.0		
	Linear Derating Factor 4		.42	W/°C

# Static Electrical Characteristics @ $T_J$ = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.03		V/°C	Reference to 25°C, I <sub>D</sub> = 1.0mA
Р	Static Drain to Source On Desistance		2.2	3.0		V <sub>GS</sub> = 10V, I <sub>D</sub> = 67A ⑦
$R_{DS(on)}$	Static Drain-to-Source On-Resistance		3.2	4.3	mΩ	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 56A ⑦
$V_{GS(th)}$	Gate Threshold Voltage	1.0	1.8	2.5	V	\\ -\\   -150\
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Coefficient		-6.9		mV/°C	$V_{DS} = V_{GS}$ , $I_D = 150 \mu A$
gfs	Forward Transconductance	152			S	$V_{DS} = 10V, I_{D} = 67A$
$R_G$	Internal Gate Resistance		0.9		Ω	
	Drain to Course Leakers Current			5.0		V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	- A	V <sub>GS</sub> = 16V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -16V

# Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

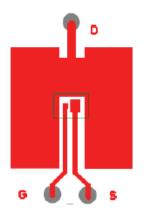
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$Q_g$	Total Gate Charge		52	78		V <sub>DS</sub> = 20V
Q <sub>gs1</sub>	Gate-to-Source Charge		8.1			$V_{GS} = 4.5V$
Q <sub>gs2</sub>	Gate-to-Source Charge		6.2			I <sub>D</sub> = 67A
$Q_gd$	Gate-to-Drain ("Miller") Charge		33		nC	See Fig.11
$Q_{godr}$	Gate Charge Overdrive		4.7			
$Q_{sw}$	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		39.2			
Q <sub>oss</sub>	Output Charge		31		nC	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V
t <sub>d(on)</sub>	Turn-On Delay Time		48			V <sub>DD</sub> = 20V, V <sub>GS</sub> = 4.5V ⑦
t <sub>r</sub>	Rise Time		210			I <sub>D</sub> = 67A
$t_{d(off)}$	Turn-Off Delay Time		56		ns	$R_G = 6.8\Omega$
t <sub>f</sub>	Fall Time		76			
C <sub>iss</sub>	Input Capacitance		5055			V <sub>GS</sub> = 0V
Coss	Output Capacitance		960			V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		525		]	f = 1.0  MHz
Coss	Output Capacitance		3540		pF	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0 MHz$
C <sub>oss</sub>	Output Capacitance		860		1	$V_{GS} = 0V, V_{DS} = 32V, f = 1.0 \text{ MHz}$
C <sub>oss</sub> eff.	Effective Output Capacitance		1306		1	$V_{GS}$ = 0V, $V_{DS}$ = 0V to 32V

Notes ① through ⑩ are on page 3



### **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
	Continuous Source Current			112		MOSFET symbol	
IS	(Body Diode)			112	_	showing the	
	Pulsed Source Current			450	A	integral reverse	
ISM	(Body Diode) ©			450		p-n junction diode.	
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 67A, V_{GS} = 0V ?$	
t <sub>rr</sub>	Reverse Recovery Time		32	48	ns	$T_J = 25^{\circ}C$ , $I_F = 67A$ , $V_{DD} = 20V$	
Q <sub>rr</sub>	Reverse Recovery Charge		23	35	nC	dv/dt = 100A/µs ⑦	



3 Surface mounted on 1 in. square Cu board (still air).



 Mounted to a PCB with small clip heatsink (still air)



 Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air).

- ${\mathbb O}$  Click on this section to link to the appropriate technical paper.  ${\mathbb O}$  Click on this section to link to the DirectFET  $^{\! @}$  Website.
- 3 Surface mounted on 1 in. square Cu board, steady state.
- T<sub>C</sub> measured with thermocouple mounted to top (Drain) of part.
- S Repetitive rating; pulse width limited by max. junction temperature.
- © Starting  $T_J = 25^{\circ}C$ , L = 0.030mH,  $R_G = 50\Omega$ ,  $I_{AS} = 67$ A,  $V_{GS} = 20$ V.
- $\ \ \$  Pulse width  $\le 400 \mu s$ ; duty cycle  $\le 2\%$ .
- ® Used double sided cooling, mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heat sink.
- @ R<sub> $\theta$ </sub> is measured at T<sub>J</sub> of approximately 90°C.

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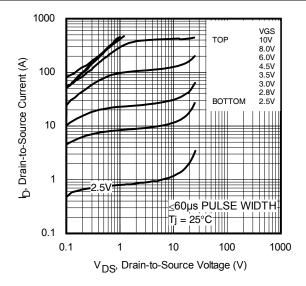


Fig. 1 Typical Output Characteristics

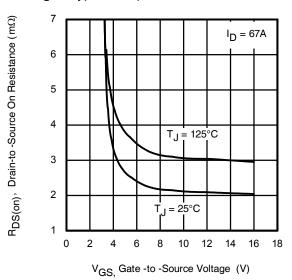


Fig. 3 Typical On-Resistance vs. Gate Voltage

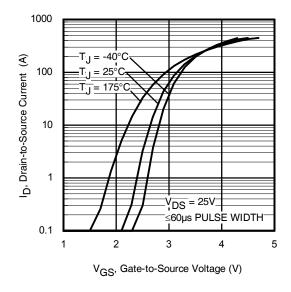


Fig 5. Transfer Characteristics

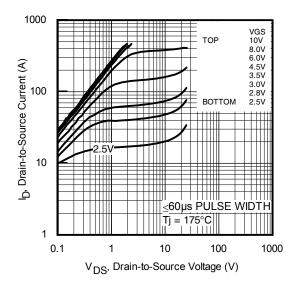


Fig. 2 Typical Output Characteristics

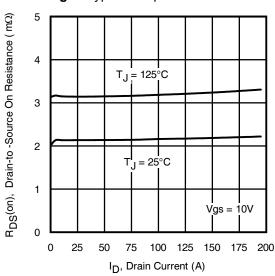


Fig. 4 Typical On-Resistance vs. Drain Current

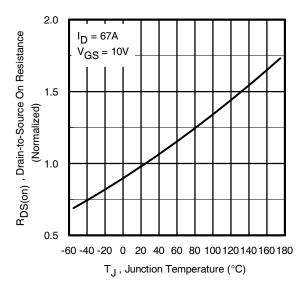
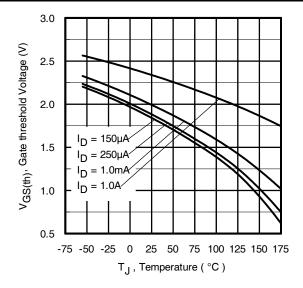


Fig 6. Normalized On-Resistance vs. Temperature





**Fig. 7** Typical Threshold Voltage vs. Junction Temperature

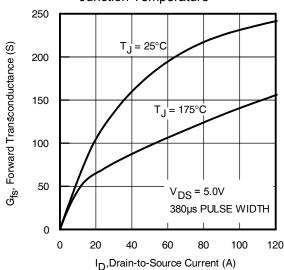
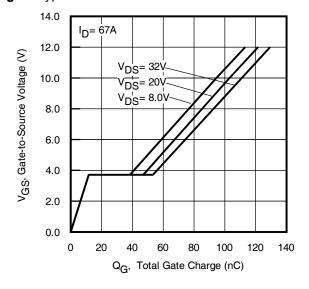


Fig 9. Typical Forward Trans conductance vs. Drain Current



**Fig 11.** Typical Gate Charge vs. Gate-to-Source Voltage

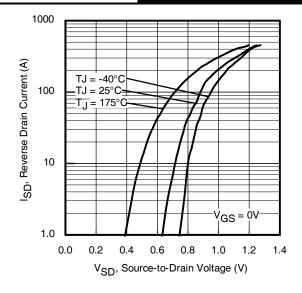


Fig 8. Typical Source-Drain Diode Forward Voltage

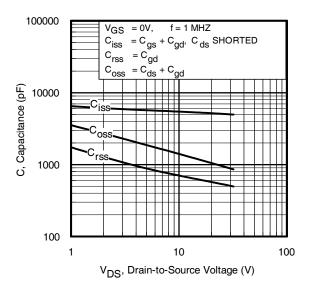


Fig 10. Typical Capacitance vs. Drain-to-Source Voltage

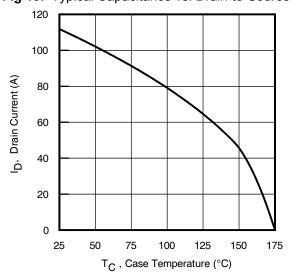
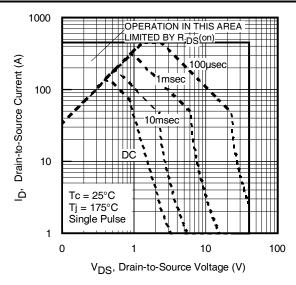


Fig 12. Maximum Drain Current vs. Case Temperature





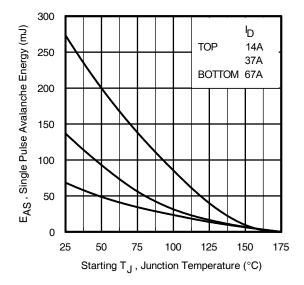


Fig 13. Maximum Safe Operating Area

Fig 14. Maximum Avalanche Energy vs. Temperature

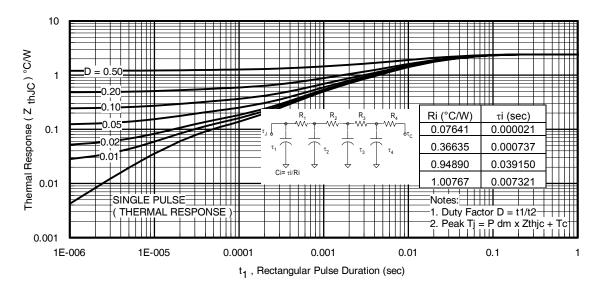


Fig 15. Maximum Effective Transient Thermal Impedance, Junction-to-Case

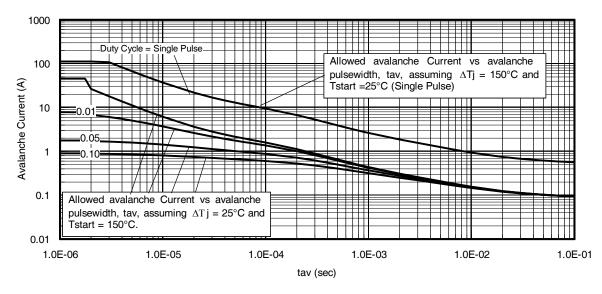


Fig 16. Typical Avalanche Current vs. Pulse Width



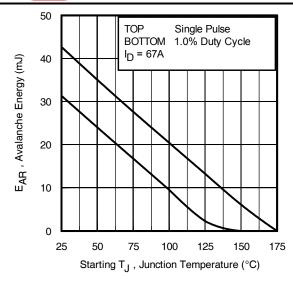


Fig 17. Maximum Avalanche Energy vs. Temperature

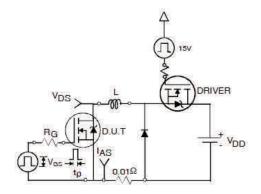


Fig 18a. Unclamped Inductive Test Circuit

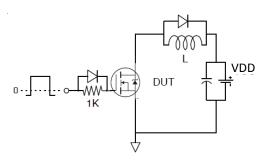


Fig 19a. Gate Charge Test Circuit

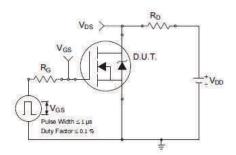


Fig 20a. Switching Time Test Circuit

# Notes on Repetitive Avalanche Curves, Figures 16, 17: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 18a, 18b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 16, 17).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 15)

$$\begin{split} P_{D \text{ (ave)}} = 1/2 \text{ ( } 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} &= \Delta \text{T} \text{/ } Z_{thJC} \\ I_{av} = 2\Delta \text{T} \text{/ } [1.3 \cdot \text{BV} \cdot Z_{th}] \\ E_{AS \text{ (AR)}} = P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

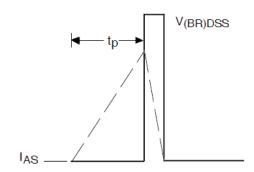


Fig 18b. Unclamped Inductive Waveforms

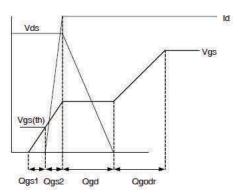


Fig 19b. Gate Charge Waveform

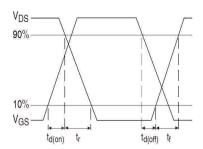
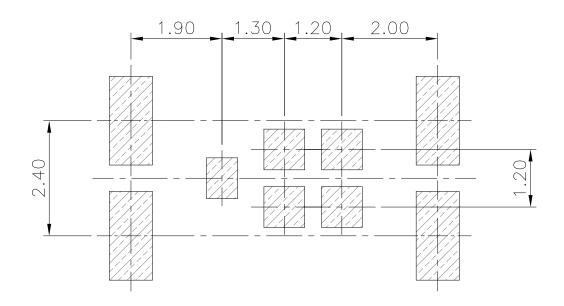
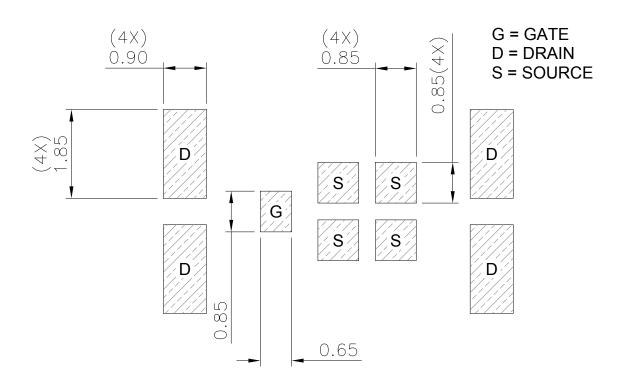


Fig 20b. Switching Time Waveforms



**DirectFET® Board Footprint, M4 (Medium Size Can).**Please see DirectFET® application note AN-1035 for all details regarding the assembly of DirectFET®. This includes all recommendations for stencil and substrate designs.





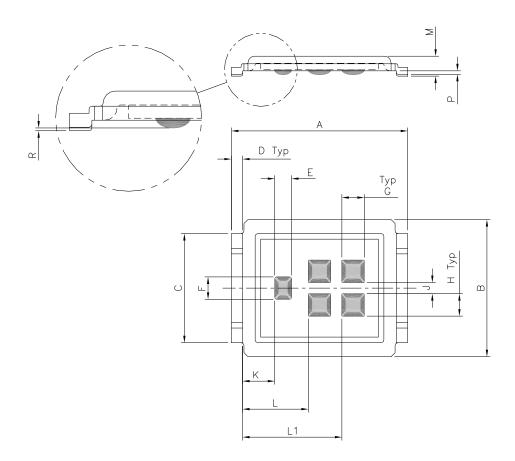
Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

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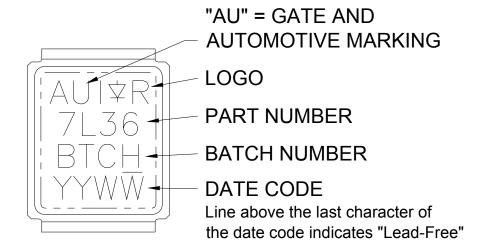
# **DirectFET® Outline Dimension, M4 Outline (Medium Size Can).**

Please see DirectFET® application note AN-1035 for all details regarding the assembly of DirectFET® . This includes all recommendations for stencil and substrate designs.



	DIMENSIONS					
	METRIC		IMPE	RIAL		
CODE	MIN	MAX	MIN	MAX		
Α	6.25	6.35	0.246	0.250		
В	4.80	5.05	0.189	0.201		
С	3.85	3.95	0.152	0.156		
D	0.35	0.45	0.014	0.018		
Е	0.58	0.62	0.023	0.024		
F	0.78	0.82	0.031	0.032		
G	0.78	0.82	0.031	0.032		
Н	0.78	0.82	0.031	0.032		
J	0.38	0.42	0.015	0.017		
K	1.10	1.20	0.043	0.047		
Г	2.30	2.40	0.090	0.094		
L1	3.50	3.60	0.138	0.142		
М	0.68	0.74	0.027	0.029		
Р	0.09	0.17	0.003	0.007		
R	0.02	0.08	0.001	0.003		

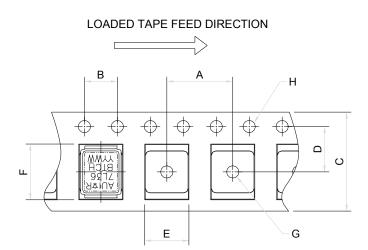
# DirectFET® Part Marking



Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

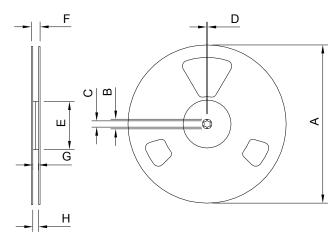


# **DirectFET®** Tape & Reel Dimension (Showing component orientation)



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS				
	MET	TRIC	IMPERIAL	
CODE	MIN MAX		MIN	MAX
Α	7.90	8.10	0.311	0.319
В	3.90	4.10	0.154	0.161
С	11.90	12.30	0.469	0.484
D	5.45	5.55	0.215	0.219
E	5.10	5.30	0.201	0.209
F	6.50	6.70	0.256	0.264
G	1.50	N.C	0.059	N.C
Н	1.50	1.60	0.059	0.063



NOTE: Controlling dimensions in mm Std reel quantity is 4800 parts, ordered as AUIRL7736M2TR.

	REEL DIMENSIONS				
	STANDA	RD OPTI	ON <mark>(QTY 4</mark>	800)	
	М	ETRIC	IMF	PERIAL	
CODE	MIN	MAX	MIN	MAX	
Α	330.0	N.C	12.992	N.C	
В	20.2	N.C	0.795	N.C	
С	12.8	13.2	0.504	0.520	
D	1.5	N.C	0.059	N.C	
E	100.0	N.C	3.937	N.C	
F	N.C	18.4	N.C	0.724	
G	12.4	14.4	0.488	0.567	
Н	11.9	15.4	0.469	0.606	

Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



### **Qualification Information**

	***************************************					
		Automotive				
Qualification Level		(per AEC-Q101)				
		Comments: This part number(s) pas	sed Automotive qualification. Infineon's			
		Industrial and Consumer qualification le	evel is granted by extension of the higher			
		Automotive level.				
Moisture Sensitivity Level		DFET2 Medium Can	MSL1, 260°C			
	Machine Model	Class M4 (+/- 400V) <sup>†</sup>				
	Machine Model	AEC-Q101-002				
FOD	Lluman Dadu Madal	Class H1C (+/- 2000V) <sup>†</sup>				
ESD	Human Body Model	AEC-Q101-001				
Charged Device Model		N/A				
		AEC-Q101-005				
RoHS Compliant		Yes				

<sup>†</sup> Highest passing voltage.

# **Revision History**

Date	Comments
10/29/2015	<ul> <li>Updated datasheet with corporate template</li> <li>Corrected ordering table on page 1.</li> <li>Updated Tape and Reel option on page 10</li> </ul>

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